Abstracts

Reduced Invasiveness of Noncontact Electrooptic Probes in Millimeter-Wave Optoelectronic Characterization (Short Papers)

A. Zeng, S.A. Shah and M.K. Jackson. "Reduced Invasiveness of Noncontact Electrooptic Probes in Millimeter-Wave Optoelectronic Characterization (Short Papers)." 1996 Transactions on Microwave Theory and Techniques 44.7 (Jul. 1996, Part I [T-MTT]): 1155-1157.

We report time-resolved measurements of the invasiveness of LiTaO/sub 3/ external probes in millimeter-wave electrooptic sampling. Using external probe tips at varying distances from a coplanar stripline, we show that invasiveness can be reduced in a noncontact configuration at the expense of measurement sensitivity. In the contact configuration, the risetime can be significantly lengthened by dispersion and signal reflection caused by the probe tip.

❑ Return to main document.